# FAIRCHILD

SEMICONDUCTOR

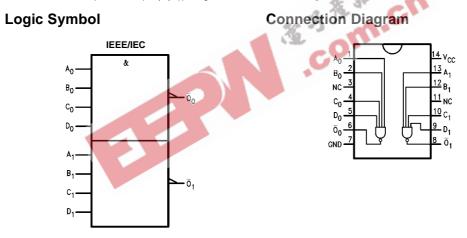
# 74F20 Dual 4-Input NAND Gate

#### **General Description**

This device contains two independent gates, each of which performs the logic NAND function.

## **Ordering Code:**

Order Number	Package Number	Package Description				
74F20SC	M14A	14-Lead Small Outline Integrated Circuit (SOIC), JEDEC MS-120, 0.150 Narrow				
74F20SJ	M14D	14-Lead Small Outline Package (SOP), EIAJ TYPE II, 5.3mm Wide				
74F20PC	N14A	14-Lead Plastic Dual-In-Line Package (PDIP), JEDEC MS-001, 0.300 Wide				
Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.						



# Unit Loading/Fan Out

Pin Names	Description	U.L.	Input I <sub>IH</sub> /I <sub>IL</sub>		
1 III Namoo	Decemption	HIGH/LOW	Output I <sub>OH</sub> /I <sub>OL</sub>		
$A_{n},B_{n},C_{n},D_{n}$	Inputs	1.0/1.0	20 µA/–0.6 mA		
Ōn	Outputs	50/33.3	–1 mA/20 mA		

April 1988

Revised July 1999

74F20

### Absolute Maximum Ratings(Note 1)

Storage Temperature	-65°C to +150°C
Ambient Temperature under Bias	$-55^{\circ}C$ to $+125^{\circ}C$
Junction Temperature under Bias	-55°C to +150°C
V <sub>CC</sub> Pin Potential to Ground Pin	-0.5V to +7.0V
Input Voltage (Note 2)	-0.5V to +7.0V
Input Current (Note 2)	-30 mA to +5.0 mA
Voltage Applied to Output	
in HIGH State (with $V_{CC} = 0V$ )	
Standard Output	-0.5V to V <sub>CC</sub>
3-STATE Output	-0.5V to +5.5V
Current Applied to Output	
in LOW State (Max)	twice the rated I <sub>OL</sub> (mA)

# Recommended Operating Conditions

Free Air Ambient Temperature Supply Voltage -

 $0^{\circ}$ C to +70°C +4.5V to +5.5V

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit or current limit is sufficient to protect inputs.

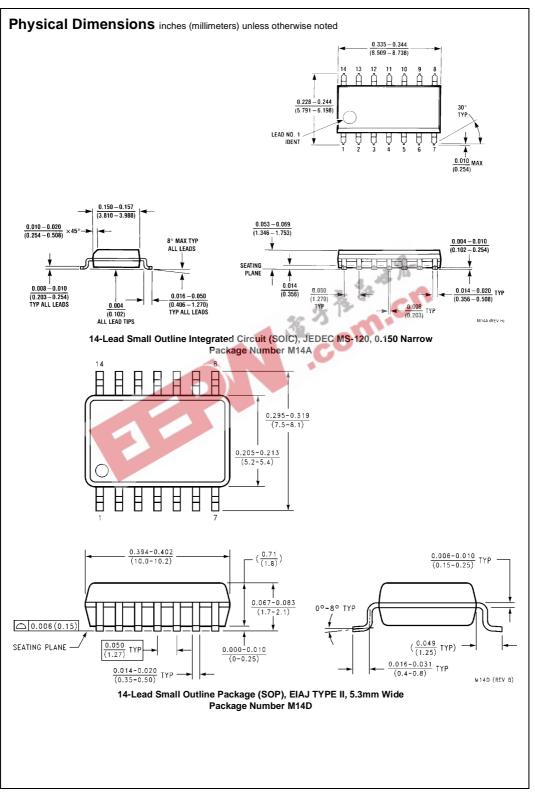
## **DC Electrical Characteristics**

Symbol	mbol Parameter		Тур	Max	Units	Vcc	Conditions		
VIH	Input HIGH Voltage	2.0			V	10	Recognized as a HIGH Signal		
V <sub>IL</sub>	Input LOW Voltage			0.8	V	~	Recognized as a LOW Signal		
V <sub>CD</sub>	Input Clamp Diode Voltage			-1.2	V	Min	I <sub>IN</sub> = -18 mA		
V <sub>OH</sub>	Output HIGH 10% V <sub>CC</sub>	2.5	- 80	2	V	Min	I <sub>OH</sub> = -1 mA		
	Voltage $5\% V_{CC}$	2.7			U.		$I_{OH} = -1 \text{ mA}$		
V <sub>OL</sub>	Output LOW 10% V <sub>CC</sub> Voltage			0.5	v	Min	I <sub>OL</sub> = 20 mA		
I <sub>IH</sub>	Input HIGH Current			5.0	μΑ	Max	V <sub>IN</sub> = 2.7V		
I <sub>BVI</sub>	Input HIGH Current Breakdown Test			7.0	μΑ	Max	V <sub>IN</sub> = 7.0V		
ICEX	Output HIGH Leakage Current			50	μΑ	Max	$V_{OUT} = V_{CC}$		
V <sub>ID</sub>	Input Leakage Test	4.75			V	0.0	I <sub>ID</sub> = 1.9 μA All other pins grounded		
I <sub>OD</sub>	Output Leakage Circuit Current			3.75	μA	0.0	V <sub>IOD</sub> = 150 mV All other pins grounded		
IIL	Input LOW Current			-0.6	mA	Max	$V_{IN} = 0.5V$		
I <sub>OS</sub>	Output Short-Circuit Current	-60		-150	mA	Max	$V_{OUT} = 0V$		
I <sub>CCH</sub>	Power Supply Current		0.9	1.4	mA	Max	V <sub>O</sub> = HIGH		
I <sub>CCL</sub>	Power Supply Current		3.4	5.1	mA	Max	V <sub>O</sub> = LOW		

**AC Electrical Characteristics** 

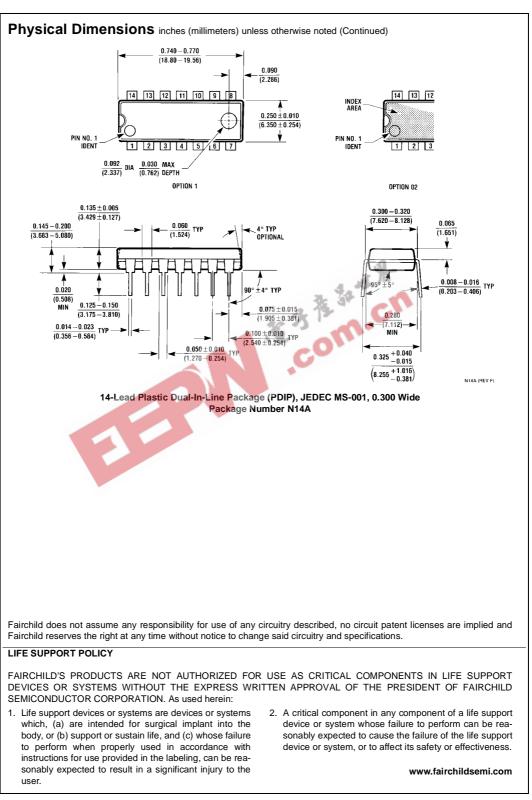
Symbol	Parameter	$T_{A} = +25^{\circ}C$ $V_{CC} = +5.0V$			$T_A = -55^{\circ} \text{ to } +125^{\circ}\text{C}$ $V_{CC} = +5.0\text{V}$		$T_{A} = 0^{\circ}C \text{ to } +70^{\circ}C$ $V_{CC} = +5.0V$		Units
		Min	C <sub>L</sub> = 50 pF Typ	Мах	C <sub>L</sub> = Min	50 pF Max	C <sub>L</sub> = Min	50 pF Max	
t <sub>PLH</sub> t <sub>PHL</sub>	Propagation Delay $A_n$ , $B_n$ , $C_n$ , $D_n$ to $\overline{O}_n$	2.4 1.5	3.7 3.2	5.0 4.3	2.0 1.5	7.0 6.5	2.4 1.5	6.0 5.3	ns

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